Alfamation system platform for high volume micro-optics testing is based on a high-end wafer handling system with robust design and flexible architecture.

Different kinds of optical test can be hosted, from standard MTF measurement to ultra fast flange focal length, down to exotic diffractive pattern analysis.

Optionally, it can be equipped with a wafer warpage correction system and an automatic wafer loader.

**KEY FEATURES AND BENEFITS**
- High flexibility to meet customer-specific requirements
- High UPH
- High positioning repeatability
- Wafer handler travel range (400x400mm)
- Barcode/OCR reading system
- Optional wafer warpage correction
- Optional automated wafer loader
- Reduced footprint
APPLICATION PORTFOLIO

- Ultra Rapid Flange focal length measurement
- Diffractive Optical Element characterization
- Optical Diffuser Characterization
- Collimator Spot size measurement
- MTF measurement
- Beam profile analysis
- Micro imaging lens
- Laser beam collimator
- Diffuser

SuperNova Test Application Framework for test sequence development and customization

- Main sequence for fast testing cycle
- Modules for fast integration of tools and drivers
- Management of test diversities
- Ease of integration with database for result storage and analysis

Unleash the Power of NI TestStand